Features

- Single 2.7V 3.6V Supply
- Fast Read Access Time 200 ns
- Automatic Page Write Operation
 - Internal Address and Data Latches for 64 Bytes
 - Internal Control Timer
- Fast Write Cycle Times
 - Page Write Cycle Time: 10 ms Maximum
 - 1- to 64-byte Page Write Operation
- Low Power Dissipation
 - 15 mA Active Current
 - 20 µA CMOS Standby Current
- Hardware and Software Data Protection
- DATA Polling for End of Write Detection
- High Reliability CMOS Technology
 - Endurance: 10,000 Cycles
 - Data Retention: 10 Years
- JEDEC Approved Byte-wide Pinout
- Commercial and Industrial Temperature Ranges

Description

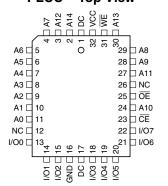
The AT28BV256 is a high-performance Electrically Erasable and Programmable Read Only Memory. Its 256K of memory is organized as 32,768 words by 8 bits. Manufactured with Atmel's advanced nonvolatile CMOS technology, the device offers access times to 200 ns with power dissipation of just 54 mW. When the device is deselected, the CMOS standby current is less than 200 μ A.

Note:

Pin Configurations

Pin Name	Function
A0 - A14	Addresses
CE	Chip Enable
ŌĒ	Output Enable
WE	Write Enable
I/O0 - I/O7	Data Inputs/Outputs
NC	No Connect
DC	Don't Connect

PLCC - Top View

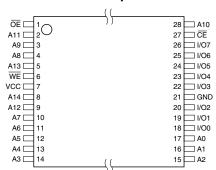


PDIP, SOIC - Top View

			-
A14 🗀	1	28	□ vcc
A12 🗀	2	27	□ WE
A7 🗀	3	26	☐ A13
A6 🗀	4	25	□ A8
A5 🗀	5	24	□ A9
A4 🗀	6	23	☐ A11
A3 🗀	7	22	□ Œ
A2 🗀	8	21	☐ A10
A1 🗀	9	20	□ Œ
A0 🗀	10	19	□ I/O7
I/O0	11	18	□ I/O6
I/O1 🗔	12	17	□ I/O5
I/O2	13	16	□ I/O4
GND 🗀	14	15	□ I/O3

1. Note: PLCC package pins 1 and 17 are DON'T CONNECT.

TSOP - Top View





256K (32K x 8)
Battery-Voltage
Parallel
EEPROMs

AT28BV256

0273H-PEEPR-10/04

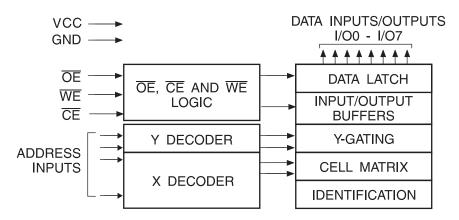




The AT28BV256 is accessed like a Static RAM for the read or write cycle without the need for external components. The device contains a 64-byte page register to allow writing of up to 64 bytes simultaneously. During a write cycle, the addresses and 1 to 64 bytes of data are internally latched, freeing the address and data bus for other operations. Following the initiation of a write cycle, the device will automatically write the latched data using an internal control timer. The end of a write cycle can be detected by \overline{DATA} polling of I/O7. Once the end of a write cycle has been detected a new access for a read or write can begin.

Atmel's AT28BV256 has additional features to ensure high quality and manufacturability. The device utilizes internal error correction for extended endurance and improved data retention characteristics. An optional software data protection mechanism is available to guard against inadvertent writes. The device also includes an extra 64 bytes of EEPROM for device identification or tracking.

Block Diagram



Absolute Maximum Ratings*

Temperature under Bias55°C to +125°C)
Storage Temperature65°C to +150°C)
All Input Voltages (including NC Pins) with Respect to Ground0.6V to +6.25\	/
All Output Voltages with Respect to Ground0.6V to V _{CC} + 0.6V	/
Voltage on $\overline{\text{OE}}$ and A9 with Respect to Ground0.6V to +13.5\	/

*NOTICE:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability

Device Operation

READ: The AT28BV256 is accessed like a Static RAM. When \overline{CE} and \overline{OE} are low and \overline{WE} is high, the data stored at the memory location determined by the address pins is asserted on the outputs. The outputs are put in the high impedance state when either \overline{CE} or \overline{OE} is high. This dual-line control gives designers flexibility in preventing bus contention in their system.

BYTE WRITE: A low pulse on the \overline{WE} or \overline{CE} input with \overline{CE} or \overline{WE} low (respectively) and \overline{OE} high initiates a write cycle. The address is latched on the falling edge of \overline{CE} or \overline{WE} , whichever occurs last. The data is latched by the first rising edge of \overline{CE} or \overline{WE} . Once a byte write has been started, it will automatically time itself to completion. Once a programming operation has been initiated and for the duration of t_{WC} , a read operation will effectively be a polling operation.

PAGE WRITE: The page write operation of the AT28BV256 allows 1 to 64 bytes of data to be written into the device during a single internal programming period. A page write operation is initiated in the same manner as a byte write; the first byte written can then be followed by 1 to 63 additional bytes. Each successive byte must be written within 150 μ s (t_{BLC}) of the previous byte. If the t_{BLC} limit is exceeded the AT28BV256 will cease accepting data and commence the internal programming operation. All bytes during a page write operation must reside on the same page as defined by the state of the A6 - A14 inputs. For each \overline{WE} high to low transition during the page write operation, A6 - A14 must be the same.

The A0 to A5 inputs are used to specify which bytes within the page are to be written. The bytes may be loaded in any order and may be altered within the same load period. Only bytes which are specified for writing will be written; unnecessary cycling of other bytes within the page does not occur.

DATA POLLING: The AT28BV256 features DATA Polling to indicate the end of a write cycle. During a byte or page write cycle, an attempted read of the last byte written will result in the complement of the written data to be presented on I/O7. Once the write cycle has been completed, true data is valid on all outputs, and the next write cycle may begin. DATA Polling may begin at anytime during the write cycle.

TOGGLE BIT: In addition to DATA Polling, the AT28BV256 provides another method for determining the end of a write cycle. During the write operation, successive attempts to read data from the device will result in I/O6 toggling between one and zero. Once the write has completed, I/O6 will stop toggling and valid data will be read. Reading the toggle bit may begin at any time during the write cycle.

DATA PROTECTION: If precautions are not taken, inadvertent writes may occur during transitions of the host system power supply. Atmel has incorporated both hardware and software features that will protect the memory against inadvertent writes.

HARDWARE PROTECTION: Hardware features protect against inadvertent writes to the AT28BV256 in the following ways: (a) V_{CC} power-on delay – once V_{CC} has reached 1.8V (typical) the device will automatically time out 10 ms (typical) before allowing a write; (b) write inhibit – holding any one of \overline{OE} low, \overline{CE} high or \overline{WE} high inhibits write cycles; and (c) noise filter – pulses of less than 15 ns (typical) on the \overline{WE} or \overline{CE} inputs will not initiate a write cycle.

SOFTWARE DATA PROTECTION: A software-controlled data protection feature has been implemented on the AT28BV256. Software data protection (SDP) helps prevent inadvertent writes from corrupting the data in the device. SDP can prevent inadvertent writes during power-up and power-down as well as any other potential periods of system instability.

The AT28BV256 can only be written using the software data protection feature. A series of three write commands to specific addresses with specific data must be presented to the device before writing in the byte or page mode. The same three write commands must begin each write operation. All software write commands must obey the page mode write timing





specifications. The data in the 3-byte command sequence is not written to the device; the address in the command sequence can be utilized just like any other location in the device.

Any attempt to write to the device without the 3-byte sequence will start the internal write timers. No data will be written to the device; however, for the duration of t_{WC} , read operations will effectively be polling operations.

DEVICE IDENTIFICATION: An extra 64 bytes of EEPROM memory are available to the user for device identification. By raising A9 to $12V \pm 0.5V$ and using address locations 7FC0H to 7FFFH the additional bytes may be written to or read from in the same manner as the regular memory array.

DC and AC Operating Range

		AT28BV256-20	AT28BV256-25
Operating Temperature (Cose)	Com.	0°C - 70°C	0°C - 70°C
Operating Temperature (Case)	Ind.	-40°C - 85°C	-40°C - 85°C
V _{CC} Power Supply		2.7V - 3.6V	2.7V - 3.6V

Operating Modes

Mode	CE	ŌĒ	WE	I/O
Read	V _{IL}	V _{IL}	V _{IH}	D _{OUT}
Write ⁽²⁾	V _{IL}	V _{IH}	V _{IL}	D _{IN}
Standby/Write Inhibit	V _{IH}	X ⁽¹⁾	X	High Z
Write Inhibit	Х	Х	V _{IH}	
Write Inhibit	Х	V _{IL}	Х	
Output Disable	X	V _{IH}	X	High Z
Chip Erase	V _{IL}	V _H ⁽³⁾	V _{IL}	High Z

Notes: 1. X can be V_{IL} or V_{IH} .

2. Refer to AC programming waveforms.

3. $V_H = 12.0V \pm 0.5V$.

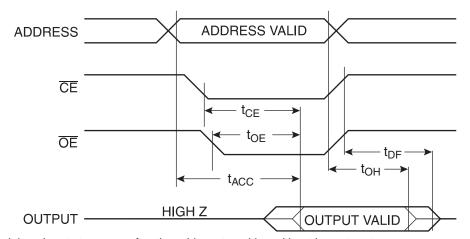
DC Characteristics

Symbol	Parameter	Condition		Min	Max	Units
I _{LI}	Input Load Current	$V_{IN} = 0V \text{ to } V_{CC} + 1V$			10	μΑ
I _{LO}	Output Leakage Current	$V_{I/O} = 0V \text{ to } V_{CC}$			10	μA
	V Chandley Cymreit CMCC	<u>CF</u>	Com.		20	μΑ
I _{SB}	V _{CC} Standby Current CMOS	$\overline{CE} = V_{CC} - 0.3V \text{ to } V_{CC} + 1V$	Ind.		50	μΑ
I _{CC}	V _{CC} Active Current	f = 5 MHz; I _{OUT} = 0 mA	•		15	mA
V _{IL}	Input Low Voltage				0.6	V
V _{IH}	Input High Voltage			2.0		V
V _{OL}	Output Low Voltage	I _{OL} = 1.6 mA			0.3	V
V _{OH}	Output High Voltage	I _{OH} = -100 μA		2.0		V

AC Read Characteristics

		AT28B	AT28BV256-20		AT28BV256-25		
Symbol	Parameter	Min	Max	Min	Max	Units	
t _{ACC}	Address to Output Delay		200		250	ns	
t _{CE} ⁽¹⁾	CE to Output Delay		200		250	ns	
t _{OE} ⁽²⁾	OE to Output Delay	0	80	0	100	ns	
t _{DF} ⁽³⁾⁽⁴⁾	CE or OE to Output Float	0	55	0	60	ns	
t _{OH}	Output Hold from OE, CE or Address, whichever occurred first	0		0		ns	

AC Read Waveforms⁽¹⁾⁽²⁾⁽³⁾⁽⁴⁾



- Notes: 1. \overline{CE} may be delayed up to t_{ACC} t_{CE} after the address transition without impact on t_{ACC} .

 2. \overline{OE} may be delayed up to t_{CE} t_{OE} after the falling edge of \overline{CE} without impact on t_{CE} or by t_{ACC} t_{OE} after an address change without impact on t_{ACC} .

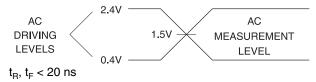
 3. t_{DF} is specified from \overline{OE} or \overline{CE} whichever occurs first $(C_L = 5 \text{ pF})$.

 - 4. This parameter is characterized and is not 100% tested.

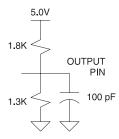




Input Test Waveforms and Measurement Level



Output Test Load



Pin Capacitance

 $f = 1 \text{ MHz}, T = 25^{\circ}C^{(1)}$

Symbol	Тур	Max	Units	Conditions
C _{IN}	4	6	pF	$V_{IN} = 0V$
C _{OUT}	8	12	pF	$V_{OUT} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

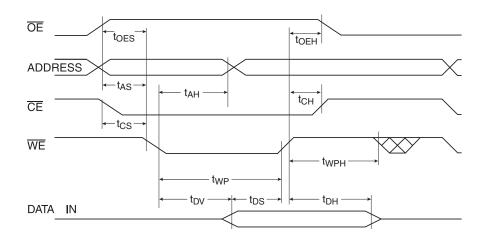
AC Write Characteristics

Symbol	Parameter	Min	Max	Units
t _{AS} , t _{OES}	Address, OE Set-up Time	0		ns
t _{AH}	Address Hold Time	50		ns
t _{CS}	Chip Select Set-up Time	0		ns
t _{CH}	Chip Select Hold Time	0		ns
t _{WP}	Write Pulse Width (WE or CE)	200		ns
t _{DS}	Data Set-up Time	50		ns
t _{DH} , t _{OEH}	Data, $\overline{\text{OE}}$ Hold Time	0		ns
t _{DV}	Time to Data Valid	NR ⁽¹⁾		

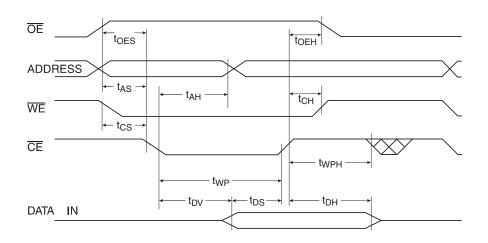
Note: 1. NR = No Restriction.

AC Write Waveforms

WE Controlled



CE Controlled



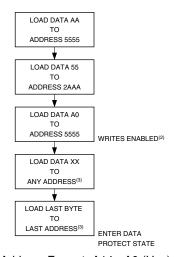




Page Mode Characteristics

Symbol	Parameter	Min	Max	Units
t _{WC}	Write Cycle Time		10	ms
t _{AS}	Address Set-up Time	0		ns
t _{AH}	Address Hold Time	50		ns
t _{DS}	Data Set-up Time	50		ns
t _{DH}	Data Hold Time	0		ns
t _{WP}	Write Pulse Width	200		ns
t _{BLC}	Byte Load Cycle Time		150	μs
t _{WPH}	Write Pulse Width High	100		ns

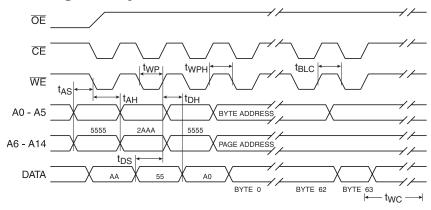
Programming Algorithm⁽¹⁾⁽²⁾⁽³⁾



Notes: 1. Data Format: I/O7 - I/O0 (Hex); Address Format: A14 - A0 (Hex).

- 2. Data protect state will be re-activated at the end of program cycle.
- 3. 1 to 64 bytes of data are loaded.

Software Protected Program Cycle Waveforms⁽¹⁾⁽²⁾⁽³⁾



Notes: 1. A0 - A14 must conform to the addressing sequence for the first three bytes as shown above.

- 2. A6 through A14 must specify the same page address during each high to low transition of WE (or CE) after the software code has been entered.
- 3. \overline{OE} must be high only when \overline{WE} and \overline{CE} are both low.

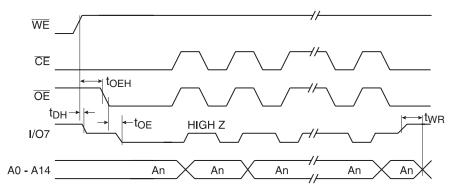
DATA Polling Characteristics⁽¹⁾

Symbol	Parameter	Min	Тур	Max	Units
t _{DH}	Data Hold Time	0			ns
t _{OEH}	OE Hold Time	0			ns
t _{OE}	ŌĒ to Output Delay ⁽²⁾				ns
t _{WR}	Write Recovery Time	0			ns

Notes: 1. These parameters are characterized and not 100% tested.

2. See "AC Read Characteristics" on page 5.

DATA Polling Waveforms



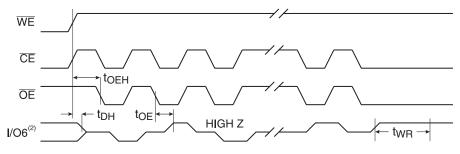
Toggle Bit Characteristics⁽¹⁾

Symbol	Parameter	Min	Тур	Max	Units
t _{DH}	Data Hold Time	10			ns
t _{OEH}	OE Hold Time	10			ns
t _{OE}	OE to Output Delay ⁽²⁾				ns
t _{OEHP}	OE High Pulse	150			ns
t _{WR}	Write Recovery Time	0			ns

Notes: 1. These parameters are characterized and not 100% tested.

2. See "AC Read Characteristics" on page 5.

Toggle Bit Waveforms



Notes: 1. Toggling either \overline{OE} or \overline{CE} or both \overline{OE} and \overline{CE} will operate toggle bit.

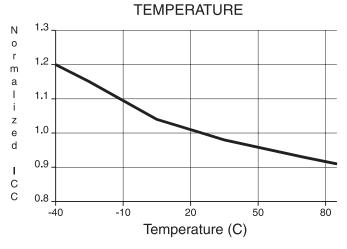
2. Beginning and ending state of I/O6 will vary.

3. Any address location may be used but the address should not vary.

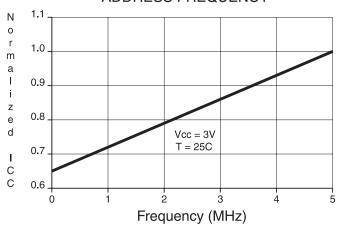




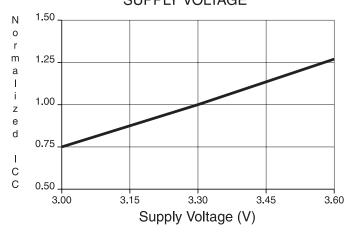
NORMALIZED SUPPLY CURRENT vs.



NORMALIZED SUPPLY CURRENT vs. ADDRESS FREQUENCY



NORMALIZED SUPPLY CURRENT vs. SUPPLY VOLTAGE



Ordering Information⁽¹⁾

t _{ACC}	I _{CC} (mA)				
(ns)	Active	Standby	Ordering Code	Package	Operation Range
200	200 15 0.02		AT28BV256-20JC	32J	Commercial
			AT28BV256-20PC	28P6	(0° to 70°C)
			AT28BV256-20SC	28S	
			AT28BV256-20TC	28T	
	15	0.02	AT28BV256-20JI	32J	Industrial
			AT28BV256-20PI	28P6	(-40° to 85°C)
			AT28BV256-20SI	28S	
			AT28BV256-20TI	28T	
	15	0.02	AT28BV256-20TU	32J Green	Industrial
			AT28BV256-20JU	28T Green	(-40° to 85°C)
250	15	0.02	AT28BV256-25JC	32J	Commercial
			AT28BV256-25PC	28P6	(0° to 70°C)
			AT28BV256-20SC	28S	
			AT28BV256-25TC	28T	
	15	0.02	AT28BV256-25JI	32J	Industrial
			AT28BV256-25PI	28P6	(-40° to 85°C)
			AT28BV256-20SI	28S	
			AT28BV256-25TI	28T	

Note: 1. See Valid Part Numbers table below.

Valid Part Numbers

The following table lists standard Atmel products that can be ordered.

Device Numbers	Speed	Package and Temperature Combinations	
AT28BV256	20	JC, JI, PC, PI, SC, SI, TC, TI, TU, JU	
AT28BV256	25	JC, JI, PC, PI, SC, SI, TC, TI	

Die Products

Reference Section: Parallel EEPROM Die Products

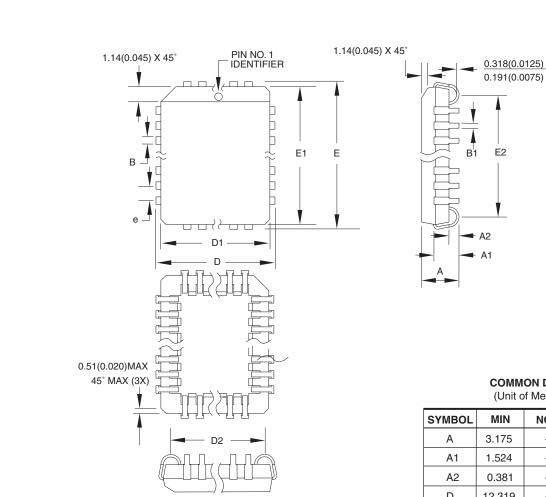
Package Type		
32J	32-lead, Plastic J-leaded Chip Carrier (PLCC)	
28P6	28-lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)	
28S	28S 28-lead, 0.300" Wide, Plastic Gull Wing Small Outline (SOIC)	
28T	28-lead, Plastic Thin Small Outline Package (TSOP)	





Packaging Information

32J - PLCC



Notes:

- 1. This package conforms to JEDEC reference MS-016, Variation AE.
- Dimensions D1 and E1 do not include mold protrusion.
 Allowable protrusion is .010"(0.254 mm) per side. Dimension D1 and E1 include mold mismatch and are measured at the extreme material condition at the upper or lower parting line.
- 3. Lead coplanarity is 0.004" (0.102 mm) maximum.

COMMON DIMENSIONS

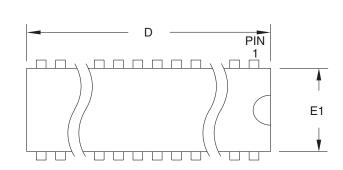
(Unit of Measure = mm)

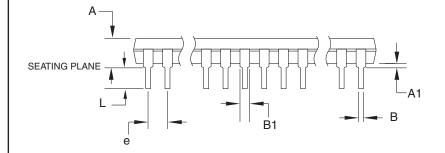
MIN	NOM	MAX	NOTE
3.175	_	3.556	
1.524	_	2.413	
0.381	_	_	
12.319	_	12.573	
11.354	_	11.506	Note 2
9.906	_	10.922	
14.859	_	15.113	
13.894	_	14.046	Note 2
12.471	_	13.487	
0.660	_	0.813	
0.330	_	0.533	
	1.270 TYF)	
	3.175 1.524 0.381 12.319 11.354 9.906 14.859 13.894 12.471 0.660 0.330	3.175 - 1.524 - 0.381 - 12.319 - 11.354 - 9.906 - 14.859 - 13.894 - 12.471 - 0.660 - 0.330 -	3.175 - 3.556 1.524 - 2.413 0.381 - - 12.319 - 12.573 11.354 - 11.506 9.906 - 10.922 14.859 - 15.113 13.894 - 14.046 12.471 - 13.487 0.660 - 0.813

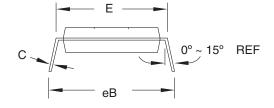
10/04/01

TITLE	DRAWING NO.	REV.
32J, 32-lead, Plastic J-leaded Chip Carrier (PLCC)	32J	В

28P6 - PDIP







Notes:

- 1. This package conforms to JEDEC reference MS-011, Variation AB.
- Dimensions D and E1 do not include mold Flash or Protrusion. Mold Flash or Protrusion shall not exceed 0.25 mm (0.010").

COMMON DIMENSIONS

(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	_	_	4.826	
A1	0.381	_	_	
D	36.703	_	37.338	Note 2
Е	15.240	_	15.875	
E1	13.462	_	13.970	Note 2
В	0.356	_	0.559	
B1	1.041	_	1.651	
L	3.048	_	3.556	
С	0.203	_	0.381	
eB	15.494	_	17.526	
е		2.540 TYF)	

09/28/01

REV.

В

4	
	\square
<u> </u>	

2325 Orchard Parkway San Jose, CA 95131 **TITLE**28P6, 28-lead (0.600"/15.24 mm Wide) Plastic Dual Inline Package (PDIP)

DRAWING NO. 28P6

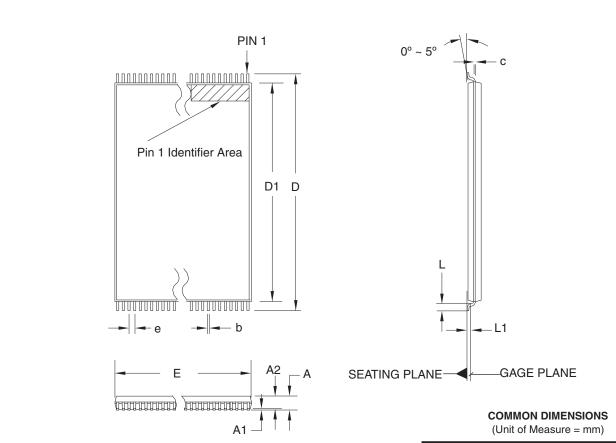




28S - SOIC

Dimensions in Millimeters and (Inches). Controlling dimension: Millimeters. 0.51(0.020) 0.33(0.013) 7.60(0.2992) 10.65(0.419) 7.40(0.2914) $\overline{10.00(0.394)}$ PIN 1 ID 1.27(0.50) BSC TOP VIEW 18.10(0.7125) 2.65(0.1043) 17.70(0.6969) 2.35(0.0926) 0.30(0.0118) 0.10(0.0040) SIDE VIEWS 0° ~ 8° 0.32(0.0125) 0.23(0.0091) 1.27(0.050) 0.40(0.016) 8/4/03 DRAWING NO. TITLE REV. 2325 Orchard Parkway 28S, 28-lead, 0.300" Body, Plastic Gull Wing Small Outline (SOIC) 28S San Jose, CA 95131 В JEDEC Standard MS-013

28T - TSOP



Notes:

- 1. This package conforms to JEDEC reference MO-183.
- 2. Dimensions D1 and E do not include mold protrusion. Allowable protrusion on E is 0.15 mm per side and on D1 is 0.25 mm per side.
- 3. Lead coplanarity is 0.10 mm maximum.

(Oint of modean o min)				
SYMBOL	MIN	NOM	MAX	NOTE
Α	_	_	1.20	
A1	0.05	_	0.15	
A2	0.90	1.00	1.05	
D	13.20	13.40	13.60	
D1	11.70	11.80	11.90	Note 2
Е	7.90	8.00	8.10	Note 2
L	0.50	0.60	0.70	
L1	0.25 BASIC			
b	0.17	0.22	0.27	
С	0.10	_	0.21	
е	0.55 BASIC			

12/06/02

С

<u>AMEL</u>	2325 Orchard Parkway		
	2325 Orchard Parkway San Jose, CA 95131		

TITLE 28T, 28-lead (8 x 13.4 mm) Plastic Thin Small Outline Package, Type I (TSOP)

DRAWING NO. REV. 28T





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Microcontrollers

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